

Editorial

# Editorial for the Special Issue on “Crystalline Materials for Radiation Detection: A New Perspective”

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The development of efficient and environmentally friendly technologies for radiation detection is a great challenge. Among the materials of present and future perspective are crystalline materials, wide-bandgap semiconductor crystals. The recent progress in crystal growth, theoretical modelling, understanding of radiation-induced defects, and radiation hardness has offered a new perspective for radiation detection. In this Special Issue of *Crystals*, we have gathered five peer-reviewed papers that shed light on recent advances in the field of application of SiC for radiation detection and beyond.

Brodar et al. [1] report on neutron irradiation and ion (2 MeV He and 7.5 C MeV) implantation-induced electrically active defects in nitrogen-doped 4H-SiC material. Radiation-induced defects and their respective deep levels were comprehensively studied by means of deep level transient spectroscopy. Potsidi et al. [2] also investigated radiation-induced defects but used another approach. They combined experimental (infrared spectroscopy, IR) and theoretical (spin-polarized density functional theory calculations) tools to study the carbon interstitial-dioxygen center of electron-irradiated Si. Focusing on radiative recombination in the nanosystem, Pokutnyui et al. [3] report on possibilities for a new generation of efficient light-emitting photodetectors based on semiconductor heterostructures. Coutinho [4] reports a theoretical study of the electronic and dynamic properties of silicon vacancies and self-interstitials in 4H-SiC using hybrid density functional methods. This work consolidates some of the most recent findings and revisits some unsolved issues by analyzing the charge-state dependence of transformation, dissociation, and migration of Si-related intrinsic defects in 4H-SiC. Finally, Bernat et al. [5] report the response of newly designed 4H-SiC Schottky barrier diode (SBD) detector prototypes to alpha and gamma radiation. A detector resolution of 3% for the wide alpha energy range, combined with the linear response to gamma, yields rates of up to 4.49 Gy/h, demonstrating the usability of this system for the detection of thermal neutrons and gamma decays.

As shown in this Special Issue of *Crystals*, the study of crystalline materials continues to grow and expand as we, as a community, strive to acquire further understanding of the underlying potential of these materials. The goal is to bring these and other new concepts closer to application for radiation detection and beyond.



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